RESEARCH ARTICLE | SEPTEMBER 08 2025

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APL Mater. 13, 091105 (2025) https://doi.org/10.1063/5.0287150





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Cite as: APL Mater. 13, 091105 (2025); doi: 10.1063/5.0287150 Submitted: 23 June 2025 • Accepted: 21 August 2025 •







Published Online: 8 September 2025

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ABSTRACT

Aluminum nitride (AlN), a wide-band-gap semiconductor, is a key material for ultraviolet optoelectronics and emerging quantum technologies. However, its performance is significantly affected by intrinsic point defects that introduce deep and shallow levels within the bandgap. Here, we combine a hybrid quantum mechanical/molecular mechanical embedded cluster approach with direct comparison to photoluminescence and cathodoluminescence measurements to investigate the optical transition properties of the four most stable intrinsic point defects in AlN: aluminum vacancies, nitrogen vacancies, aluminum interstitials, and nitrogen interstitials. Calculated configuration-coordinate diagrams across all relevant charge states enable the assignment of experimentally observed optical bands to specific defect-related transitions. Our results highlight N vacancies as the dominant contributors to optical signals under most growth conditions. Although we find that Al vacancies are frequently associated with blue-to-UV optical transitions, their actual contribution remains uncertain due to the dependence of their formation on donor-rich environments. N split-interstitials also play a significant role depending on concentrations and growth conditions. This theoretical analysis, grounded firmly in suitable experimental compaisons, advances the understanding of defect-related optical properties in AlN and offers guidance for the design of optoelectronic and quantum devices.

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I. INTRODUCTION

Aluminum nitride (AlN) is an advanced semiconductor material widely recognized for its applications in optoelectronic devices and quantum information systems, particularly in environments demanding high-power operation and robustness at high temperatures. Its wide 6.2 eV bandgap makes the material an excellent candidate for ultra-violet-spectrum (UV) light emitting diodes (LEDs)²⁻⁴ and laser diodes. High concentrations of various point defects in AlN, which can create deep and shallow recombination

states within the bandgap, hinder optimal optical performance and operational stability in these UV-LED devices. ^{4,6} Notably, with the growing prominence of quantum technology, these deep defect centers in wide-band-gap semiconductors characterized by strongly localized spin states are increasingly considered to be promising hosts for quantum bits (qubits), enabling applications such as single-photon emitters. ^{7,8} The remarkable versatility of AlN underscores the need for further investigation into its defect properties.

The challenge of identifying the origin of shallow and deep states lies in the difficulty of determining whether they arise from a single defect species or a collective of multiple species. Optical characterization techniques, such as photoluminescence (PL) and cathodoluminescence (CL), serve as valuable tools for probing the transition energies between energy bands and defect states. These techniques also aid in assigning defect species to the states, mostly by matching optical signals with defect charge transition levels calculated using density functional theory (DFT) methods. This approach assumes that any optical transition between the valence band (VB)/conduction band (CB) and any defect states corresponds to a change in the defect's charge state, provided that the charge carriers are strongly localized at the defect centers. While this approach provides a good approximation of transitions between two structurally relaxed defect states, it does not fully capture the origin of these transitions, particularly when phonon-coupled transitions are involved, as optical transitions occur much faster than structural relaxations. As summarized in Table I, a broad spectrum of optical signals has so far been attributed to intrinsic aluminum and nitrogen

DFT-based methods for defect chemistry have been extensively developed over the years, evolving into a powerful tool for calculating the structural and electronic properties of native defects and impurities in semiconductor materials. These techniques have been applied to defect analysis in AlN, 18,22-40 mainly using plane-wave based approaches, in which an infinite periodic system is represented by a single unit cell image and simulated under specific periodic boundary conditions. While these approaches offer many advantages for modeling periodic crystalline material systems, limitations such as finite-size effects⁴¹ and scaling challenges restrict their suitability for higher-level DFT analyses of point defects in very large systems. Furthermore, for charged defects, these methods often struggle to describe accurately long-range interactions and polarization effects, leading to inaccuracies in describing the ionization process. Such errors can only be approximately corrected a posteriori. 42 Early attempts to address these issues included the use of an embedded quantum cluster method, enabling the modeling of point defects in systems approaching the dilute limit.^{43,4} As a result, the ionization process of the charge-changing defect

TABLE I. Overview of assignments of optical emission and absorption bands to native point defects in AIN found in the literature.

| Defect | Absorption/Emission | Energy (eV) | Refs. | | |
|------------------------|---------------------|------------------|-----------|--|--|
| $\overline{V_{ m Al}}$ | Absorption | 2.1-2.9, 2.9-3.3 | 9 | | |
| | Emission | 2 | 10 and 11 | | |
| | | 2.78, 3.4 | 9 | | |
| | | 3.3 | 12-14 | | |
| | | 4.6 | 15 | | |
| | | | | | |
| $V_{\rm N}$ | Absorption | 2.7-3.5 | 16 | | |
| | | 3.4 | 17 | | |
| | | 4.7 | 18 | | |
| | | 5.0-5.8 | 19 | | |
| | Emission | 3, 3.2 | 20 | | |
| | | 5 | 15 | | |
| | | 5.87 | 21 | | |

species benefits from an unambiguous reference, which is more physically reasonable. However, those studies only examined two types of point defect species in zinc-blende AlN using a small five-atom AlN cluster for the DFT region. In the present work, we employ a more advanced hybrid quantum mechanical molecular mechanical (QM/MM) method⁴⁵ to investigate the four most stable intrinsic point defect types, using a much larger quantum mechanical cluster and a more robust interatomic potential model (more details in Sec. II), providing an accurate treatment for polarisation of the host material by defects. As a result, our QM/MM system provides more accurate formation energies for charged point defects and the energy levels of all defect states within the bandgap.

In our previous work using the QM/MM method, intrinsic point defects in AlN were investigated using a defect transition diagram, 46 which is a commonly used diagram for comparing the thermodynamic stability of different point defect types and analyzing the charge transitions between various charge states of defect species. Our simulations suggest that the aluminum vacancy (in the Kröger-Vink notation: $V_{\rm Al}$), nitrogen vacancy ($V_{\rm N}$), aluminum interstitial (Al_i), and nitrogen interstitial (N_i) are the four most stable intrinsic point defects in AlN. 46 Other reported intrinsic defects, such as antisite defects, are excluded from this study, as they are predicted to have significantly lower concentrations and minimal impact on the optical signals of the material. In this work, we study the optical transition properties of these four intrinsic defect types by systematically applying configuration-coordinate diagrams to all the charge states. This allows us to use the predicted Fermi level to screen all possible defect origins of the optical transitions under different crystal growth conditions and to expand the analysis to a wider range of defect species, such as interstitial defects. We identify N vacancies as the primary contributor to optical signals due to their high stability and prevalence under most crystal growth conditions. Al vacancy and N split-interstitial defects can also play significant roles in the optical behavior of AlN, but the contribution of Al vacancies remains uncertain, as they tend to form in high concentrations only in the presence of a substantial number of ionized donor impurities. Our investigation offers a new strategy and novel insights into the understanding of defect-induced optical properties in semiconductor materials.

II. METHODOLOGY

The simulations are carried out by applying our hybrid QM/MM embedded cluster method in the ChemShell package (Tcl version^{47,48} and Python version⁴⁹). The QM/MM system consists of five concentric regions/layers: (1) the innermost QM region; (2) a transition layer described by Gaussian-type pseudopotentials to compensate for force mismatches between the QM and MM regions and maintain a short-range embedding potential; (3) an "active" MM layer where all atoms and electron shells are relaxed; (4) a "frozen" MM layer, where atomic positions are fixed; and (5) an outermost layer of point charges added to reproduce the Madelung potential of the infinite crystal surrounding the defect center. DFT calculations are performed on an 86-atom cluster (~5 Å radius) using NWChem⁵⁰ for the QM region. Both the hybrid-level B97-2⁵¹ and BB1K⁵² exchange-correlation functionals are applied in this study as it has been previously reported that the fraction of the exact Hartree-Fock (HF) exchange significantly affects the energetics of defect formation and the positions of charge transition levels. Both have been fitted to large thermo-chemical datasets, with the B97-2 functional including 21% exact exchange, while the BB1K functional reproducing in addition selected reaction barriers includes 42% exact exchange and is expected to describe strongly localized states more accurately. The Def2-TZVP basis set⁵³ is used for both Al and N, with the outermost diffuse and high angular momentum basis functions removed to reduce computational cost. The MM simulations are performed using GULP. 54,55 The two MM regions contain ~10,000 atoms in total (~15 Å radius). Details on the technical aspects of our QM/MM method, such as the pseudopotential functions and the interatomic potential model used for other QM/MM regions, can be found in our previous studies. 46,56 In that previous work, the PBE0 functional, 57,58 which incorporates 25% exact exchange, was also employed. The resulting defect energies were found to lie at intermediate positions between those computed using B97-2 and BB1K, somewhat closer to those obtained with B97-2. We do not use the defect energies obtained from PBE0 in this study, instead focusing on those calculated using the B97-2 and BB1K functionals.

The Fermi levels are determined using a self-consistent method (code: SC-FERMI⁵⁹) under the condition of overall charge neutrality, balancing the concentrations of free charge carriers and all defect species (charged and neutral). The equilibrium concentrations of all free charge carriers were calculated by integrating the electronic density of states (DOS) of AlN, obtained using VASP. 60-62 However, as the B97-2 and BB1K functionals are not available in plane-wave-based DFT codes at present, to our knowledge, the DOS of AlN was computed using the PBE0 functional. We obtained a bandgap energy of 6.11 eV using PBE0, close to the experimental gap value. Figure S1 in the supplementary material compares the Fermi levels calculated using defect concentrations from B97-2, PBE0, and

BB1K functionals, all referenced against the PBE0-based DOS. The Fermi level obtained by PBE0 lies at a similar position to that from B97-2 and is lower than that from BB1K by less than 0.2 eV. For a wide-gap material of 6.11 eV, we consider that these are only minor differences between different functionals, so we use the Fermi level obtained from PBE0 in subsequent discussions.

III. RESULTS AND DISCUSSION

The charge transition levels obtained from the defect transition diagrams provide the energy levels of the single-electron transitions, considering only the predominant charged point defects while neglecting all other charge states and defect types. Figure 1 summarizes the charge transition levels (including all the meta-stable states) based on our defect transition diagram reported previously. 46 Matching our predicted charge transition levels to previous experimental assignments of optical signals remains challenging (see Table I: the reported V_{Al} signals at 2–4.6 eV and the V_{N} signals at 2.7-5.87 eV) due to the complexity of inequivalent defect sites and their charge states. Furthermore, when considering all the intrinsic defect types present in the material, our predicted self-consistent Fermi level is ~3.11-3.70 eV above the valence band maximum (VBM) under N-rich crystal growth conditions (4.67-5.19 eV for Alrich conditions, shown in Fig. S1)46 at 300-2800 K. The energy states below this value can be occupied, and electronic transitions can only occur between these states and the conduction band minimum (CBM) or shallow states near the CBM. For instance, considering a Fermi level of 3.66 eV under N-rich conditions at a growth temperature of 2800 K (a typical condition for bulk AlN crystal growth using physical vapor transport techniques 19,63,64), multiple defect states remain between the VBM and the Fermi level (see Fig. 1), which still

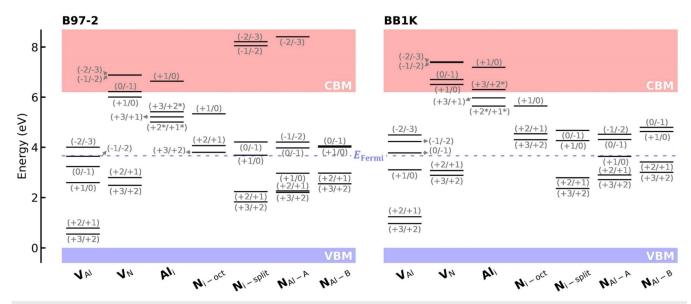


FIG. 1. The charge state transition levels of native point defects in AlN (see the corresponding defect transition diagram from our previous study⁴⁶) calculated using B97-2 and BB1K DFT hybrid functionals for N-rich conditions. The charge states marked with asterisks (*) are the metastable states (which are structurally stable states from simulations but not the thermodynamically stable ones at any Fermi level within the bandgap). Note that the self-consistent Fermi level, E_{Fermi} , is calculated using the PBE0 functional at 2800 K (see more details in our previous study⁴⁶).

makes it difficult to unambiguously assign specific defect species to experimentally observed optical signals.

Defects in different charge states undergo distinct lattice relaxations, whereas electronic transitions occur on much shorter timescales. Therefore, a clearer picture of electron and hole capture via charged defects is properly described by a configuration-coordinate diagram (Fig. 2), where free energy surfaces are plotted against the interpolated configurations between the equilibrium structures of two charge states. The process of optical absorption and its required energy (E_{AB}) is depicted as the excitation of an electron from the ground state to the excited state, while optical emission (and its photoluminescence (PL) energy, E_{PL}) corresponds to the capture of an electron from the excited state to the ground state. The energy difference between the minima of the two curves is the zero-phonon line (E_{ZPL}). As illustrated in Fig. 2, since opti-

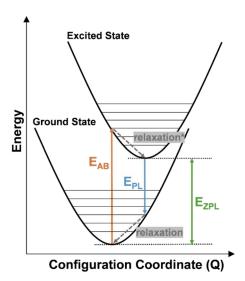


FIG. 2. A schematic representation of the configuration coordinate diagram.

cal processes occur much faster than lattice relaxations, vertical lines between the two states represent these transitions, giving rise to the Stokes shifts between absorption and emission signals, which are commonly observed in experiments. The configuration-coordinate diagram is a common tool for identifying the defect origins of optical transitions in wide-gap materials. ⁶⁵ It has previously been used to predict optical absorption/emission lines arising from Al vacancies, N vacancies, and O impurities in AlN. ^{34,40,44}

The optical transition energies between different charge states, i.e., $E_{\rm AB}$ and $E_{\rm PL}$, are obtained by performing single-point QM/MM calculations by altering the net charge of the equilibrium structures. Here, we use D(Q|Q+1)e to denote an electron excitation transition (defect-to-CBM transition), where a defect species (D) changes from the ground state (charge Q) to the excited state (charge Q+1) and D(Q|Q-1)h to represent a hole generating process (VBM-to-defect transition). All corresponding energies, including the equilibrium energies from structural relaxation ($E_{\rm rel}$ for relaxation in the ground state and $E_{\rm rel*}$ for the relaxation in the excited state), are summarized in Tables II–V.

We first discuss the optical properties of the nitrogen vacancy $V_{\rm N}^q$, as it is the most stable defect type and a dominant donor species in AlN. 46,56 Using the B97-2 functional, we found a broad range of absorption energies (0.55-5.43 eV) associated with electron excitation from the $V_{\rm N}$ states to the CBM and from VBM to the defect states (Table II). When using BB1K optimized structures and energies, the defect states shift slightly closer to CBM, yielding absorption energies of 0.08–5.02 eV. In the literature, $V_{\rm N}$ was first assigned to an absorption band at 370 nm (~3.4 eV) as an F-centre defect.¹⁷ Later, two absorption bands in the ranges of 5.0-5.8 eV and 2.7-3.5 eV were attributed to this defect, 16,19 and it was proposed that the defect is responsible for the yellow-to-red coloration of as-grown AlN crystal samples.⁶⁶ More recently, a study reported a 4.7 eV absorption signal by V_N . From our calculations, while the bands at 3.4 eV and 2.7-3.5 eV do not correspond to any of our predicted transitions for $V_{\rm N}$, the 5.0–5.8 eV band can be associated with the $V_N(+2|+3)e$ transition, and the 4.7 eV band is likely to be associated with the $V_N(+1|+2)e$ or the $V_N(+3|+2)h$ transition.

TABLE II. Summary of ionization energies of nitrogen vacancy defect (V_N) for the full range of charge states using the B97-2 and BB1K functionals. The energy terms are defined in the main text, and all values are in eV.

| | | | B97-2 | | | BB1K | | | | |
|--------------------------------|-------------|-------------------|-------|---------------|---------------------|-------------|-------------------|-------|--------------------|---------------------|
| Defect states | $E_{ m PL}$ | E_{AB} | ZPL | $E_{\rm rel}$ | $E_{\mathrm{rel}*}$ | $E_{ m PL}$ | E_{AB} | ZPL | E_{rel} | $E_{\mathrm{rel}*}$ |
| $\overline{V_{\rm N}(+2 +3)e}$ | 1.88 | 5.43 | 3.71 | 1.83 | 1.71 | 1.48 | 5.02 | 3.31 | 1.83 | 1.70 |
| $V_{\rm N}(+1 +2)e$ | 2.14 | 4.72 | 3.40 | 1.27 | 1.32 | 1.86 | 4.43 | 3.12 | 1.26 | 1.31 |
| $V_{\rm N}(0 +1)e$ | -0.77 | 1.25 | 0.20 | 0.97 | 1.05 | -1.25 | 0.73 | -0.31 | 0.94 | 1.04 |
| $V_{\rm N}(-1 0)e$ | -0.94 | 0.92 | -0.02 | 0.92 | 0.94 | -1.39 | 0.41 | -0.50 | 0.89 | 0.92 |
| $V_{\rm N}(-2 -1)e$ | -1.82 | 0.55 | -0.68 | 1.14 | 1.23 | -2.37 | 0.08 | -1.21 | 1.16 | 1.29 |
| $\overline{V_{\rm N}(+3 +2)h}$ | 0.77 | 4.32 | 2.49 | 1.72 | 1.83 | 1.19 | 4.72 | 2.89 | 1.70 | 1.83 |
| $V_{\rm N}(+2 +1)h$ | 1.48 | 4.07 | 2.80 | 1.32 | 1.27 | 1.77 | 4.34 | 3.08 | 1.31 | 1.26 |
| $V_{\rm N}(+1 0)h$ | 4.95 | 6.97 | 6.00 | 1.05 | 0.97 | 5.47 | 7.45 | 6.51 | 1.04 | 0.94 |
| $V_{\rm N}(0 -1)h$ | 5.28 | 7.14 | 6.22 | 0.94 | 0.92 | 5.79 | 7.59 | 6.70 | 0.92 | 0.89 |
| $\frac{V_{\rm N}(-1 -2)h}{}$ | 5.65 | 8.02 | 6.88 | 1.23 | 1.14 | 6.12 | 8.57 | 7.41 | 1.29 | 1.16 |

TABLE III. Summary of ionization energies of aluminum vacancy defect (V_{Al}) for the full range of charge states using the B97-2 and BB1K functionals. The energy terms are defined in the main text, and all values are in eV.

| | | | B97-2 | | | | | BB1K | | |
|------------------------------------|-------------|----------|-------|--------------------|---------------------|-------------|-------------------|------|--------------|---------------------|
| Defect states | $E_{ m PL}$ | E_{AB} | ZPL | E_{rel} | $E_{\mathrm{rel}*}$ | $E_{ m PL}$ | E_{AB} | ZPL | $E_{ m rel}$ | $E_{\mathrm{rel}*}$ |
| $\overline{V_{\text{Al}}(+2 +3)e}$ | 3.95 | 6.95 | 5.65 | 1.70 | 1.30 | 3.15 | 6.92 | 5.24 | 2.09 | 1.68 |
| $V_{\rm Al}(+1 +2)e$ | 4.06 | 6.22 | 5.41 | 1.36 | 0.80 | 3.71 | 6.21 | 4.96 | 1.25 | 1.25 |
| $V_{\rm Al}(0 +1)e$ | 3.06 | 5.09 | 3.61 | 0.54 | 1.49 | 2.31 | 4.38 | 3.09 | 0.78 | 1.28 |
| $V_{\rm Al}(-1 0)e$ | 2.45 | 3.49 | 2.96 | 0.52 | 0.53 | 1.67 | 3.37 | 2.43 | 0.75 | 0.95 |
| $V_{\rm Al}(-2 -1)e$ | 1.67 | 3.43 | 2.56 | 0.89 | 0.87 | 0.86 | 3.14 | 1.97 | 1.11 | 1.17 |
| $V_{\rm Al}(-3 -2)e$ | 0.59 | 3.60 | 2.20 | 1.60 | 1.41 | 0.00 | 3.29 | 1.71 | 1.71 | 1.58 |
| $\overline{V_{\text{Al}}(+3 +2)h}$ | -0.75 | 2.26 | 0.55 | 1.30 | 1.70 | -0.72 | 3.05 | 0.97 | 1.68 | 2.09 |
| $V_{\rm Al}(+2 +1)h$ | -0.02 | 2.14 | 0.79 | 0.80 | 1.36 | -0.01 | 2.49 | 1.24 | 1.25 | 1.25 |
| $V_{\mathrm{Al}}(+1 0)h$ | 1.11 | 3.14 | 2.60 | 1.49 | 0.54 | 1.72 | 3.83 | 3.11 | 1.28 | 0.78 |
| $V_{\rm Al}(0 -1)h$ | 2.71 | 3.75 | 3.24 | 0.53 | 0.52 | 2.83 | 4.91 | 3.78 | 0.95 | 0.75 |
| $V_{\rm Al}(-1 -2)h$ | 2.77 | 4.53 | 3.64 | 0.87 | 0.89 | 3.06 | 5.34 | 4.23 | 1.17 | 1.11 |
| $V_{\text{Al}}(-2 -3)h$ | 2.60 | 5.61 | 4.00 | 1.41 | 1.61 | 2.91 | 6.20 | 4.49 | 1.58 | 1.71 |

TABLE IV. Summary of ionization energies of aluminum interstitial defect (Al_i) for the full range of charge states using the B97-2 and BB1K functionals. The energy terms are defined in the main text, and all values are in eV.

| | | | B97-2 | BB1K | | | | | | |
|--|----------------------|----------------------|-----------------------|----------------------|----------------------|----------------------|----------------------|------------------------|----------------------|----------------------|
| Defect states | $E_{ m PL}$ | E_{AB} | ZPL | $E_{\rm rel}$ | $E_{\mathrm{rel}*}$ | $E_{ m PL}$ | E_{AB} | ZPL | E_{rel} | $E_{\mathrm{rel}*}$ |
| $ \frac{\text{Al}_{i}(+2 +3)e}{\text{Al}_{i}(+1 +2)e} $ $ \frac{\text{Al}_{i}(+1 +2)e}{\text{Al}_{i}(0 +1)e} $ | -0.33 -1.44 | 3.12 2.73 0.61 | 0.78 1.19 -0.44 | 1.52 1.00 | 2.33 1.54 1.05 | -1.13 -2.00 | 2.44 2.22 0.06 | -0.10 0.56 -0.99 | 1.68 1.01 | 2.54 1.66 1.05 |
| $\frac{\text{Al}_{i}(+3 +2)h}{\text{Al}_{i}(+2 +1)h}$ $\text{Al}_{i}(+1 0)h$ | 3.08 3.47 5.59 | 6.53 7.64 | 5.42 5.01 6.64 | 2.33 1.54 1.05 | 1.52 1.00 | 3.76 3.98 6.14 | 7.33 8.20 | 6.30 5.65 7.19 | 2.54 1.66 1.05 | 1.68 1.01 |

We identified two plausible emission processes in the infrared-to-visible spectrum from the CBM to $V_{\rm N}^q$ states: 1.88 and 2.14 eV using B97-2 and 1.48 and 1.86 eV from BB1K (Table II); as in several other cases, the excited states relax into stable configurations, resulting in free energy barriers to further electron capture, represented by negative PL energies. Additionally, we found a broad range of emission energies (0.77–6.12 eV) associated with electron recombination from the $V_{\rm N}$ states to the VBM. Two deep-ultraviolet (DUV) bands at 5 and 5.82 eV have been previously reported ^{15,21} and attributed to $V_{\rm N}$. A more recent study²⁰ has assigned the 415 nm (~3.0 eV) and 390 nm (~3.2 eV) blue-to-UV luminescence to the F-center $V_{\rm N}$. Comparing them to our results, the 5 and 5.82 eV bands can be associated with the $V_{\rm N}(+1|0)h$, $V_{\rm N}(0|-1)h$, and $V_{\rm N}(-1|-2)h$ transitions, but we could not assign any of our emission energies to the 3 and 3.2 eV signals.

Aluminum vacancies ($V_{\rm Al}$) are predicted to have the highest concentration in the presence of extra ionized donors in the material, 46 making them another probable source of defect-induced optical transitions. Sedhain *et al.* reported that $V_{\rm Al}(-2|-3)h$ was responsible for the absorption at 2.1–2.9 eV and the emission at 2.78 eV. Later, first-principles calculations using plane-wave-based

basis functions and the HSE06 functional confirmed the value of this emission.³⁴ While our calculations predict no such absorption band associated with this transition, the reported emission band aligns well with our prediction at 2.60 and 2.91 eV using B97-2 and BB1K functionals for the $V_{Al}(-2|-3)h$ transition. Additionally, we found that $V_{Al}(-1|-2)h$ can also contribute to this emission signal (our prediction: 2.77 and 3.06 eV). However, we found that the absorption energies from the $V_{AI}(+3|+2)h$ and $V_{AI}(+2|+1)h$ transitions agree with the reported absorption bands. In the same study, $V_{Al}(-3|-2)e$ was assigned to the 2.9-3.3 eV absorption to the CBM,9 which is close to our prediction range of 3.29 and 3.60 eV using B97-2 and BB1K. However, we also consider that the $V_{Al}(-2|-1)e$ transition, predicted at 3.14 and 3.43 eV, could contribute to this signal. Other optical transitions associated with $V_{\rm Al}$ -related signals have also been reported. The $V_{\rm Al}(-1|-2)h$ transition was proposed as the origin of the 2 eV emission line.¹¹ However, our calculations predict a PL energy of 2.77 or 3.06 eV for this transition, ~0.7-1 eV higher than their observation. Nevertheless, the $V_{Al}(-1|-2)h$ and the $V_{Al}(0|+1)e$ transitions might be the source of the 3.3 eV emission signal reported by several studies. 12-14 The closest PL energy we predict is from the $V_{Al}(+1|0)h$ transition

TABLE V. Summary of ionization energies of nitrogen split-interstitial defect $(N_{i-split})$ for the full range of charge states using the B97-2 and BB1K functionals. The energy terms are defined in the main text, and all values are in eV.

| B97-2 | | | | | | BB1K | | | | |
|-----------------------|-------------------|-------------------|------|--------------|---------------------|-------------|-------------------|------|--------------------|---------------------|
| Defect states | E_{PL} | E_{AB} | ZPL | $E_{ m rel}$ | $E_{\mathrm{rel}*}$ | $E_{ m PL}$ | E_{AB} | ZPL | E_{rel} | $E_{\mathrm{rel}*}$ |
| $N_{i-split}(+2 +3)e$ | 1.88 | 6.23 | 4.37 | 2.49 | 1.85 | 1.24 | 6.03 | 3.84 | 2.60 | 2.19 |
| $N_{i-split}(+1 +2)e$ | 2.01 | 5.37 | 3.96 | 1.96 | 1.40 | 1.30 | 5.17 | 3.41 | 2.11 | 1.76 |
| $N_{i-split}(0 +1)e$ | -1.58 | 3.92 | 2.52 | 4.10 | 1.41 | -2.35 | 3.46 | 1.93 | 4.28 | 1.53 |
| $N_{i-split}(-1 0)e$ | 0.69 | 2.80 | 1.99 | 1.30 | 0.82 | 0.14 | 2.31 | 1.53 | 1.39 | 0.78 |
| $N_{i-split}(+3 +2)h$ | -0.03 | 4.32 | 1.83 | 1.85 | 2.49 | 0.17 | 4.97 | 2.36 | 2.19 | 2.60 |
| $N_{i-split}(+2 +1)h$ | 0.83 | 4.20 | 2.24 | 1.40 | 1.96 | 1.03 | 4.90 | 2.79 | 1.76 | 2.11 |
| $N_{i-split}(+1 0)h$ | 2.28 | 7.79 | 3.69 | 1.41 | 4.10 | 2.74 | 8.55 | 4.27 | 1.53 | 4.28 |
| $N_{i-split}(0 -1)h$ | 3.40 | 5.52 | 4.21 | 0.82 | 1.30 | 3.89 | 6.06 | 4.67 | 0.78 | 1.39 |

at 1.11 and 1.72 eV. However, since the concentration of positively charged $V_{\rm Al}$ is likely low in the material with high concentrations of ionized donors, the optical signal from this transition may be very weak

One of the biggest challenges in assigning specific optical bands to $V_{\rm Al}$ in previous experimental studies is the presence of oxygen contamination in the samples. $V_{\rm Al}$ are often associated with oxygen substitutional defects ($O_{\rm N}$), forming defect complexes. The higher the oxygen concentration, the more $V_{\rm Al}$ are likely to form in AlN. For instance, in the study of Sedhain *et al.*, the oxygen concentration in the sample was measured to be ~2 × 10 18 cm $^{-3}$, comparable to our calculated concentrations of intrinsic defects. Our previous defect concentration calculations also indicate that $V_{\rm Al}$ becomes more prevalent than $V_{\rm N}$ only when additional ionized donors are present in the material, the which suggests that oxygen may play a crucial role in increasing the formation of $V_{\rm Al}$ in AlN. A more detailed QM/MM investigation into the effects of oxygen impurities will be explored in future studies.

We also calculated the optical transition energies for aluminum interstitial (Al_i) and nitrogen interstitial (N_i) defects, as these defects can reach high concentrations under specific chemical conditions, yet their optical properties remain largely unexplored. Most previous studies have overlooked interstitial-induced optical transitions, as early DFT studies using lower-level functionals suggested high formation energies for intrinsic interstitial defects. However, more recent simulations using hybrid-GGA-level functionals with spin polarization have shown that the formation energies of intrinsic interstitial point defects and interstitial-complex defects can be comparable to those of intrinsic vacancies.⁴⁶ From our previous calculations, positively charged Ali was predicted to have a concentration comparable to V_N under N-rich conditions when high concentrations of ionized acceptors are precent.⁴⁶ For N_i, the nitrogen split-interstitial (N_{i-split}) configuration can form in concentrations comparable to V_N under N-rich conditions. (We will not expand on the other configuration, the octahedral-centric nitrogen interstitial, which is predicted to have high formation energies across all charge states, resulting in low concentrations.)46

Our calculations reveal several absorption bands associated with Al_i-to-CBM transitions, which are Al_i(+2| + 3)e (at 2.44 and 3.12 eV) and Al_i(+1| + 2)e (at 2.22 and 2.73 eV) (see Table III).

Notably, two previously reported experimental optical absorption signals at 2.7–3.5 eV and 2.1–2.9 eV, which were originally assigned to $V_{\rm N}$ and $V_{\rm Al}$, respectively, can also be assigned to these transitions of Al_i. However, the emissions from both transitions are unlikely to be significant due to high free energy barriers (represented by the negative energies in Table IV). Additionally, we identified some possible defect-to-VBM emission bands at 3.08–3.98 eV, aligning with several experimentally observed bands previously attributed to $V_{\rm Al}$ (see the discussion above on $V_{\rm Al}$). For Ni–split (summarized in Table V), we found a wide range of visible-to-DUV absorption bands at 2.31–6.03 eV for defect-to-CBM transitions and DUV absorption bands at 4.20–8.55 eV for VBM-to-defect transitions. Predicted emission bands include 0.14–2.01 eV for CBM-to-defect transitions and 0.17–3.89 eV for defect-to-VBM transitions.

Based on the results presented above, we now provide a more global overview of defect-induced optical transitions in AlN. In an undoped system with only intrinsic point defects, the intrinsic Fermi level of AlN is predicted to lie between 3.11 and 3.70 eV under Nrich conditions and 4.67-5.19 eV under Al-rich conditions above the VBM.46 This implies that defect states positioned between the VBM and the Fermi levels are fully occupied at low to moderate temperatures. As a result, only transitions either from occupied states below the Fermi level to the CBM or from the VBM to the unoccupied in-gap states above the Fermi level, with bands above 2.50 eV (N-rich) or above 1.01 eV (Al-rich) and below 6.11 eV (the bandgap value), can occur as one-particle pocesses. The most dominant defect species are V_N and N_{i-split} under N-rich conditions and V_N under Al-rich conditions. 46 Under N-rich conditions, multiple transitions between the charge states of V_N and N_{i-split} exhibit suitable absorption bands above 2.50 eV, as calculated using both B97-2 and BB1K functionals. Several emission transitions above 2.50 eV can also be assigned to V_N and N_{i-split}. Under Al-rich conditions, more transitions of V_N are identified, exhibiting both absorption and emission bands above 1.01 eV.

Next, we examine the conditions when a large number of ionized donors or acceptors are present in the material. When high concentrations of ionized donors are introduced, the Fermi level is predicted to shift to 5.00–5.76 eV under N-rich conditions and 6.12–6.41 eV under Al-rich conditions above the VBM.⁴⁶ In this case, the majority of in-gap states can contribute to optical

transitions, with possible transition bands appearing above 1.07 eV (N-rich) or above 0 eV (Al-rich) and below 6.11 eV. Under N-rich conditions, $V_{\rm Al}$ is the most dominant compensation defect. Our calculations indicate that apart from $V_{\rm Al}(+2|+3)e$ and $V_{\rm Al}(+1|+2)e$ transitions, which are above 6.20 eV, all other absorption transitions of $V_{\rm Al}$ are allowed to occur. For emissions, excluding the $V_{\rm Al}(-3|-2)e$, $V_{\rm Al}(+3|+2)h$, and $V_{\rm Al}(+2|+1)e$ transitions, all other transitions are allowed. Under Al-rich conditions, as the Fermi level shifts very close to the CBM, the 0–0.59 eV emission transition of $V_{\rm Al}(-3|-2)e$ is now allowed.

When high concentrations of ionized acceptors are introduced, the Fermi level is predicted to shift to 1.74–2.36 eV under N-rich conditions and 3.14–4.62 eV under Al-rich conditions, relative to the VBM. Consequently, optical transitions can occur with bands above 3.84 eV (N-rich) or above 1.58 eV (Al-rich) and below 6.11 eV. Under N-rich conditions, the predominant compensating defect is $V_{\rm N}$, with increasing concentrations of Al_i and N_{i-split} at elevated temperatures. Multiple transitions between $V_{\rm N}$ charge states exhibit suitable absorption and emission bands, while additional transitions associated with N_{i-split} also contribute to optical activity. No transition attributed to Al_i can be found in the energy range of 3.84–6.20 eV. Under Al-rich conditions, the concentrations of Al_i and N_{i-split} decrease significantly, and $V_{\rm N}$ remains to be the most dominant compensating defect species. Optical transitions are now primarily from $V_{\rm N}$.

Finally, we revisit the optical bands that could not be initially assigned to our predictions. The 2, 3, 3.2, and 4.6 eV emission peaks have been previously observed in the AlN epitaxial layer 11,15 and in AlN nano-powder. These signals may now be attributed to V_N , $N_{\text{i-split}}$, or V_{Al} , depending on the specific growth conditions. For the 2 eV emission observed in samples grown under N-rich conditions with low impurity concentrations, several transitions predicted for the undoped scenario using the B97-2 functional are consistent with this observation (assuming a $\pm 10\%$ prediction uncertainty). These include CBM-to-defect transitions of $V_N(+2|+3)e$ at 1.88 eV, $V_N(+1|+2)e$ at 2.14 eV, $V_{\text{i-split}}(+2|+3)e$ at 1.88 eV, and

 $N_{i\text{-split}}(+1|+2)e$ at 2.01 eV. Similarly, for the 4.6 eV signals also observed in N-rich grown epitaxial films, 15 the $V_{\rm N}(+1|0)h$ transition at 4.95 eV (B97-2) is a likely contributing source. We note that our BB1K calculations for these transitions predict emission energies ~0.5 eV lower than the B97-2 functional. However, we may conclude that the source of the observed 2 eV peak is an N defect in AlN.

For the 3 and 3.2 eV emissions, which were observed in nanoparticle samples with significant levels of oxygen, 20 they may now be attributed to $V_{\rm Al}$ due to the increasing presence under conditions with high levels of ionized donors. A wide range of possible transitions involving $V_{\rm Al}$ are identified: $V_{\rm Al}(+2|+3)e$ at 3.15 eV (BB1K), $V_{\rm Al}(0|+1)e$ at 3.06 eV (B97-2), $V_{\rm Al}(0|-1)h$ at 2.71 eV (B97-2) and 2.83 eV (BB1K), $V_{\rm Al}(-1|-2)h$ at 2.77 eV (B97-2) and 3.06 eV (BB1K), and $V_{\rm Al}(-2|-3)h$ at 2.91 eV (BB1K). These results suggest that $V_{\rm Al}$, for most of its charge states, likely plays a substantial role in the blue-to-UV spectral range, which is critical for AlN-based blue-light and UV LED applications.

Finally, two absorption signals observed at 2.7-3.5 and 3.4 eV in single-crystal AlN, previously attributed to V_N , may now be reassigned based on our analysis. The former, observed in samples with high concentrations of oxygen, is more likely attributed to V_{Al} . The latter, observed in samples with high concentrations of carbon, may be assigned to $N_{i-split}(0|+1)e$ at 3.46 eV (BB1K) and $N_{i-split}(-1|0)e$ at 2.80 eV (B97-2) as no corresponding $V_{\rm N}$ transition matches within the energy range. These discrepancies, including the ones from our emission assignments, imply the dependence of predicted transition energies on the choice of DFT functionals. Consequently, the assignment of calculated transitions to experimentally observed optical signals is rather complex and uncertain. Therefore, we caveat these assignments with regard to the choice of functional, although note that the N_{i-split} defect is predicted to be the source of these peaks, regardless of the functional in our study. Further refinement may be achieved by incorporating non-radiative recombination processes, which account for structural relaxations during electron and hole capture.

TABLE VI. Summary of our predicted assignments to experimentally observed optical signals in AIN. (Corresponding references are provided in Table I and discussed in the main text.)

| | Energy (eV) | Predicted origin |
|------------|-------------|---|
| Absorption | 2.1-2.9 | $V_{\rm Al}(+2 +1)h, V_{\rm Al}(+3 +2)h$ |
| _ | 2.9-3.3 | $V_{\rm Al}(-2 -1)e, V_{\rm Al}(-3 -2)e$ |
| | 2.7-3.5 | $V_{\rm Al}$ (charge transitions in the main text) |
| | 3.4 | $N_{i-split}(-1 0)e, N_{i-split}(0 +1)e,$ |
| | 4.7 | $V_{\rm N}(+1 +2)e, V_{\rm N}(+3 +2)h$ |
| | 5.0-5.8 | $V_{\rm N}(+2 +3)e$ |
| Emission | 2 | $V_{\rm N}(+1 +2)e$, $V_{\rm N}(+2 +3)e$, $N_{\rm i-split}(+1 +2)e$, $N_{\rm i-split}(+2 +3)e$ |
| | 2.78 | $V_{\rm Al}(-2 -3)h, V_{\rm Al}(-1 -2)h$ |
| | 3, 3.2 | $V_{\rm Al}$ (charge transitions in the main text) |
| | 3.3 | $V_{\rm Al}(-1 -2)h, V_{\rm Al}(0 +1)e$ |
| | 3.4 | $V_{Al}(-2 -3)h, V_{Al}(-1 -2)h$ |
| | 4.6 | $V_{\rm N}(+1 0)h$ |
| | 5 | $V_{\rm N}(-1 -2)h, V_{\rm N}(0 -1)h, V_{\rm N}(+1 0)h$ |
| | 5.87 | $V_{\rm N}(-1 -2)h, V_{\rm N}(0 -1)h, V_{\rm N}(+1 0)h$ |

IV. SUMMARY AND CONCLUSIONS

In summary, using the QM/MM embedded cluster method, we have investigated the optical properties of intrinsic vacancy and interstitial defects in AlN in an environment approaching the dilute limit. These advanced DFT methods provide more accurate formation energies of charged point defects and more precise energy levels of the defect states in the bandgap due to more precise treatment of long-range electrostatic interactions and ionization processes. By calculating the optical transition energies for vacancies and interstitials across the full range of charge states, we have reviewed all the previously observed optical bands and assigned them to our predicted transitions of defect species, which is summarized in Table VI. In contrast to previous studies, which considered only contributions from vacancy defects, our calculations suggest that interstitial defects can also play a significant role in the optical properties of AlN. Furthermore, depending on the chemical conditions of AlN crystal growth and the positions of the Fermi level, the dominant defect species and their contributions to optical properties can vary. We suggest that the nitrogen vacancies, which have the highest concentration under most of the chemical conditions, contribute most significantly to optical transitions in the material. For aluminum vacancies, while we found several optical signals could be associated with them, their contribution tends to emerge when a large number of ionized donors is present in the material. It is very likely that oxygen impurities enhance the presence of aluminum vacancies, resulting in stronger blue-to-UV optical transitions. Nitrogen split-interstitial defects play a secondary role, depending on their concentrations in the material. This study provides new insights into defect-induced optical transitions in both intrinsic and impurity-containing AlN, which can be beneficial for optoelectronic applications and quantum technologies.

SUPPLEMENTARY MATERIAL

The supplementary material provides an additional figure that supports the findings of this study. Figure S1 compares the self-consistent Fermi level predicted from the defect formation energies calculated by different DFT functionals (B97-2, PBE0, and BB1K).

ACKNOWLEDGMENTS

The authors would like to acknowledge the usage of HPC services, Young and ARCHER2, for the completion of this work. The usage of Young and ARCHER2 (a UK National Supercomputing Service (http://www.archer2.ac.uk)) is via our membership of the UK's HEC Materials Chemistry Consortium, which is funded by the EPSRC (Grant Nos. EP/L000202, EP/R029431, EP/T022213, and EP/X035859). This work used the UK Materials and Molecular Modeling Hub for computational resources, MMM Hub, which is partially funded by the EPSRC (Grant Nos. EP/T022213/1, EP/W032260/1, and EP/P020194/1). ChemShell development is supported by CoSeC, the Computational Science Centre for Research Communities, through the Materials Chemistry Consortium.

AUTHOR DECLARATIONS

Conflict of Interest

The authors have no conflicts to disclose.

Author Contributions

Lei Zhu: Conceptualization (equal); Data curation (lead); Formal analysis (lead); Investigation (lead); Methodology (equal); Project administration (equal); Resources (equal); Supervision (equal); Validation (lead); Visualization (lead); Writing - original draft (lead); Writing - review & editing (lead). Xingfan Zhang: Investigation (equal); Methodology (equal); Validation (equal); Visualization (equal); Writing - review & editing (equal). You Lu: Methodology (equal); Software (equal); Writing - review & editing (equal). Thomas W. Keal: Methodology (equal); Software (equal); Writing - review & editing (equal). John Buckeridge: Conceptualization (equal); Formal analysis (equal); Investigation (equal); Methodology (equal); Software (equal); Writing - original draft (equal); Writing – review & editing (equal). C. Richard A. Catlow: Conceptualization (equal); Methodology (equal); Project administration (lead); Resources (equal); Software (equal); Supervision (lead); Writing - review & editing (equal). Alexey A. Sokol: Conceptualization (equal); Data curation (equal); Formal analysis (equal); Investigation (equal); Methodology (equal); Project administration (equal); Resources (equal); Software (equal); Supervision (equal); Writing – review & editing (equal).

DATA AVAILABILITY

The data that support the findings of this study are available within the article and its supplementary material.

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